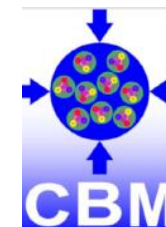


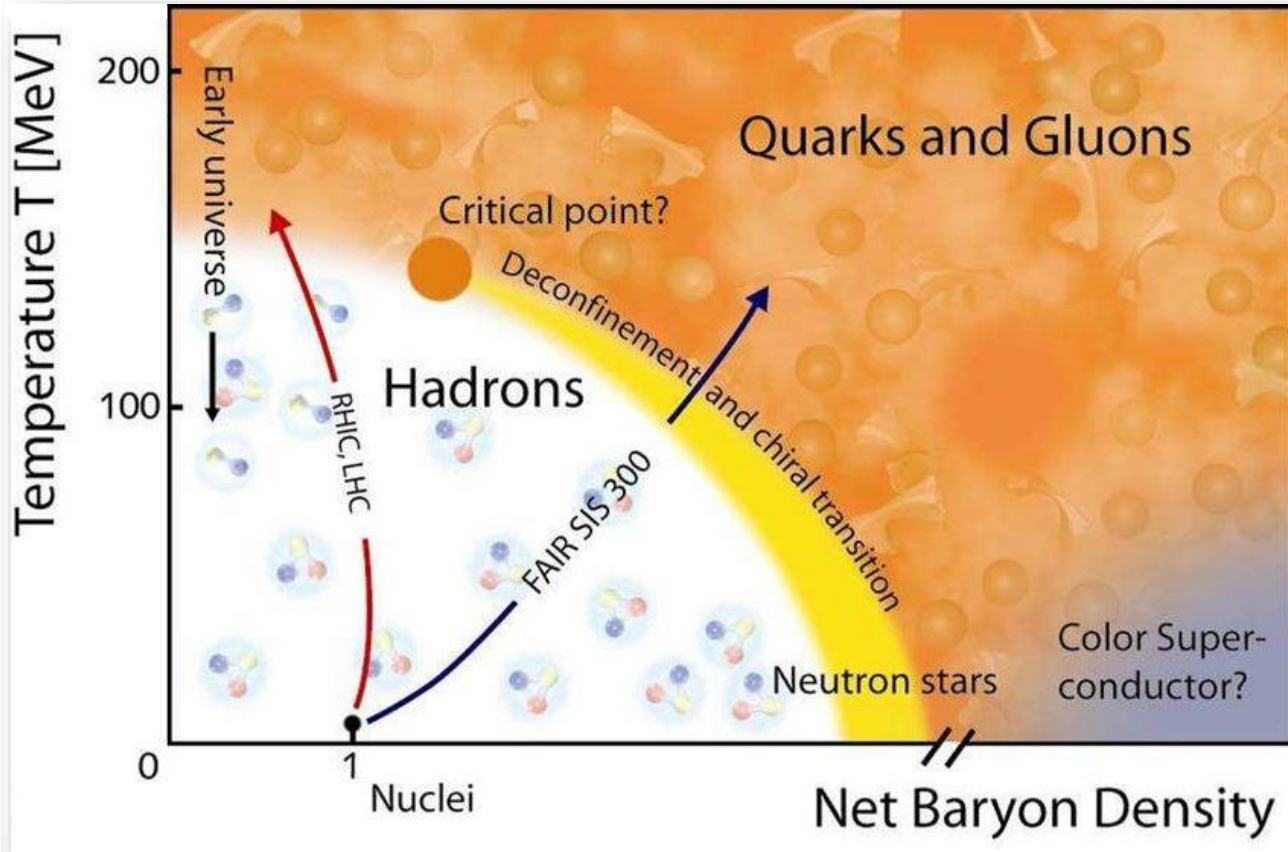
# Feasibility Studies for Di-Electron Spectroscopy with CBM

Cornelius Feier-Riesen  
Justus-Liebig-Universität Gießen



# Motivation

[[https://theory.gsi.de/~friman/trento\\_06.html](https://theory.gsi.de/~friman/trento_06.html)]



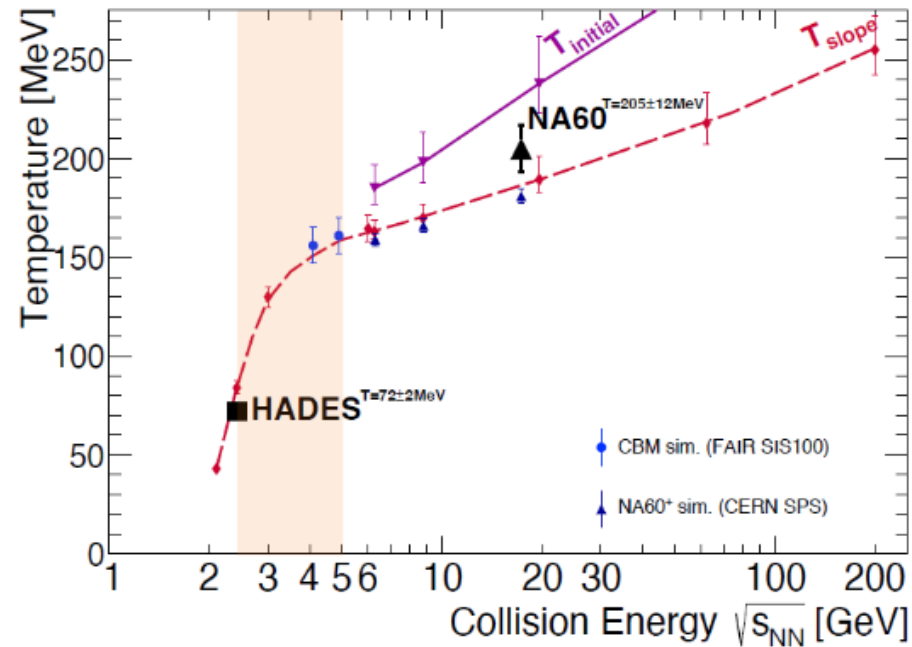
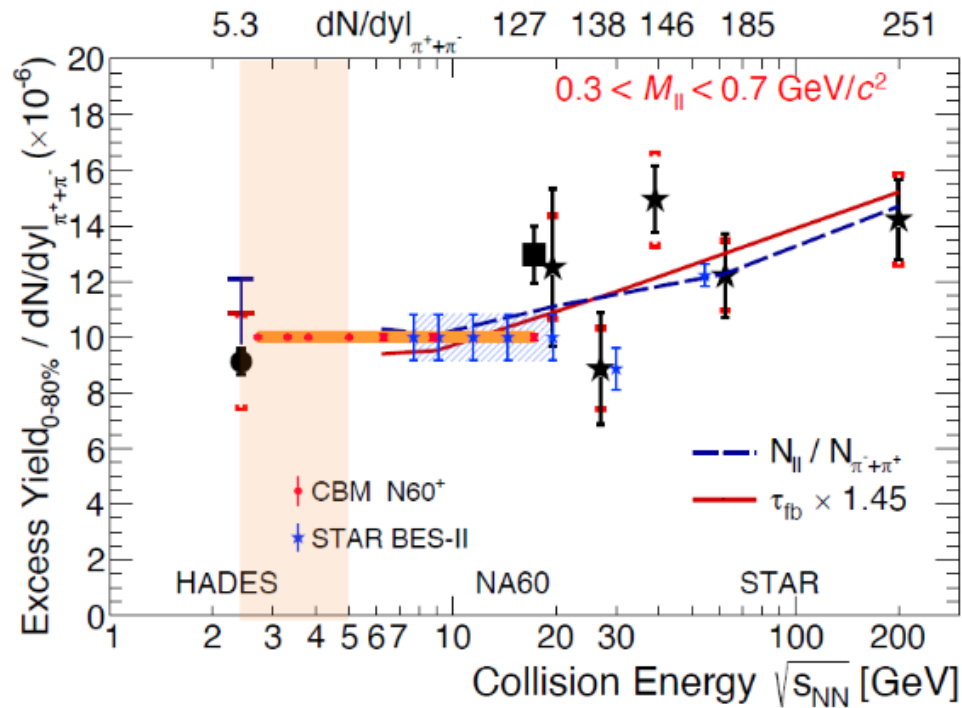
- **CBM: Compressed Baryonic Matter**
- **Explore QCD phase diagram at high densities and moderate temperatures**
- **Di-lepton spectroscopy: determine temperature and lifetime of fireball**

# Motivation

- Excess yield in LMR  $\rightarrow$  fireball lifetime: extra radiation due to latent heat around PT (& CEP?)?
- Invariant mass slope (LMR & IMR)  $\rightarrow$  flattening of caloric curve due to PT ?

\* one year 5 days beam on target, 6 energies Au+Au,  $2 \cdot 10^{10}$  ev. each, 100kHz

Tripolt et al., NPA 982 (2019) 775  
 Li and Ko, PRC 95 (2017) no.5, 055203  
 Seck et al., PRC (2022), arXiv:2010.04614 [nucl-th]  
 O. Savchuk et al., arXiv:2209.05267 [nucl-th]



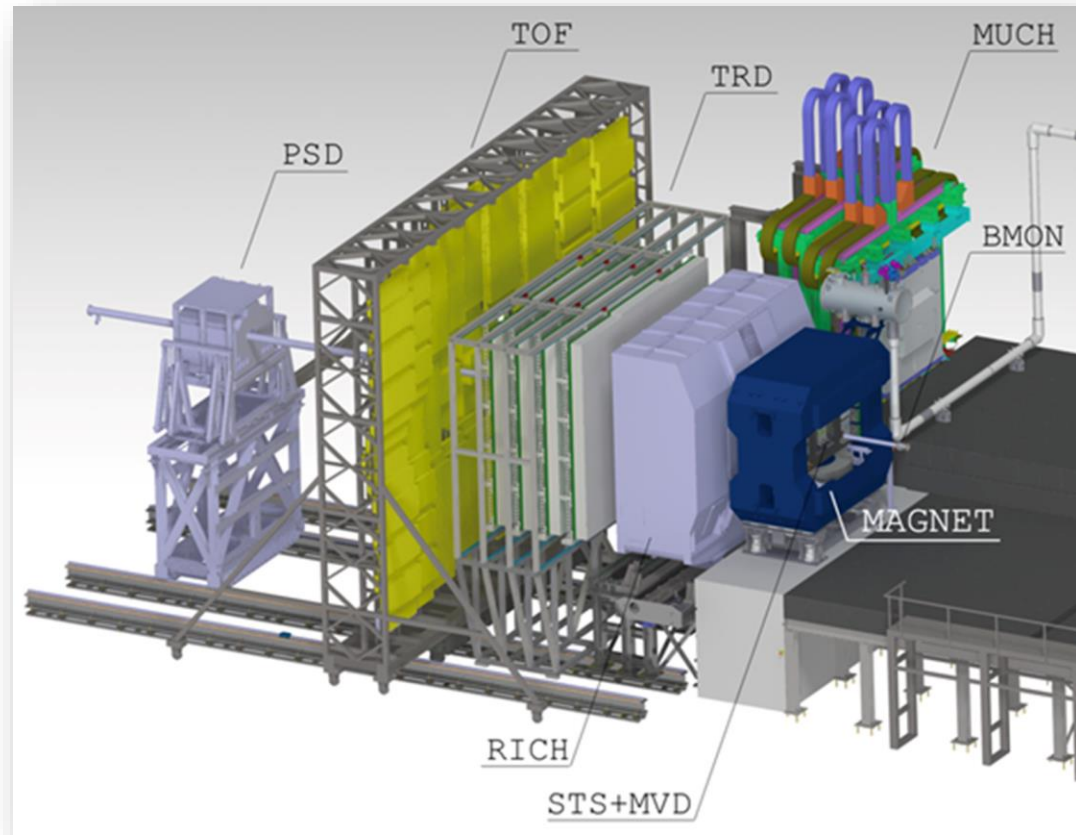
T. Galatyuk, JPS Conf. Proc. 32 (2020) 010079k

Slide taken from Claudia Höhne

**A rise in the excess yield and constancy in Temperature would be an indication of a 1<sup>st</sup> order phase transition.**

# Track Selection for Di-Electron Analysis at CBM

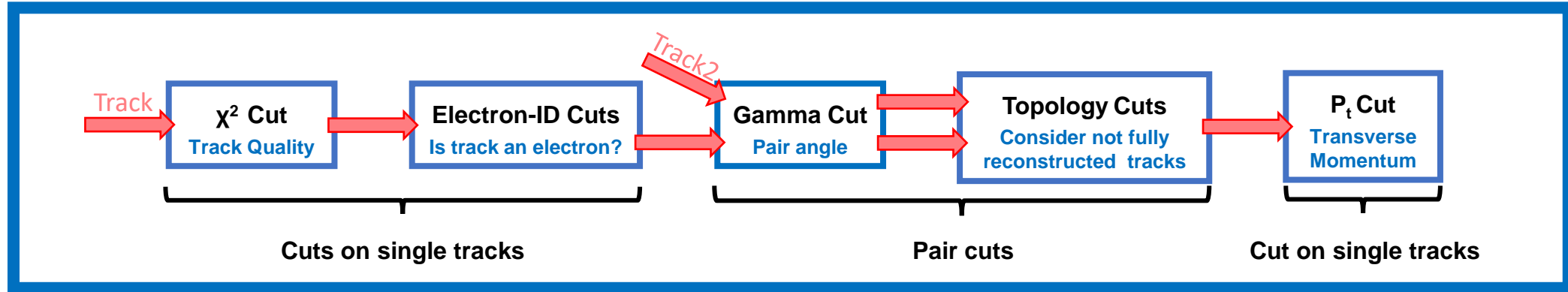
[Peter Senger, CBM Collaboration Meeting; Mar 24]



## Problems we have to deal with:

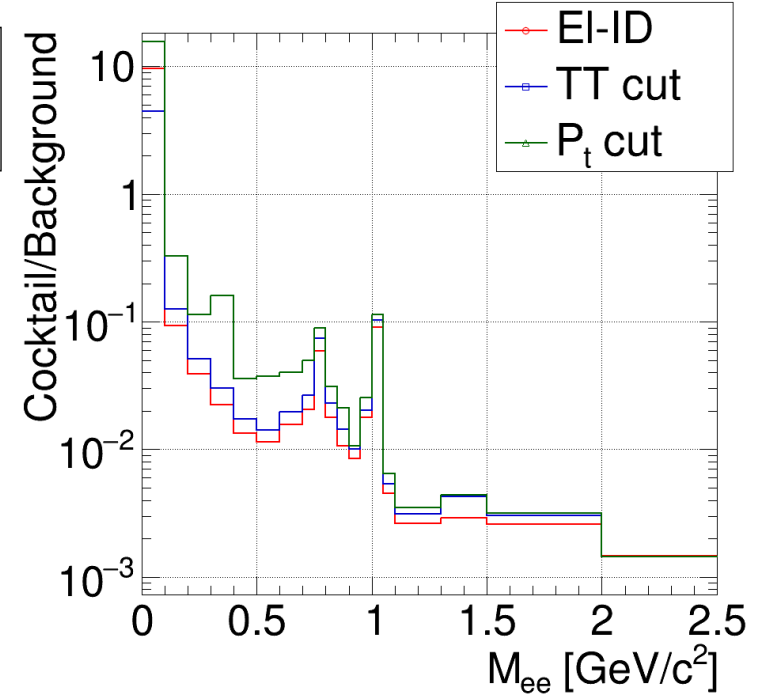
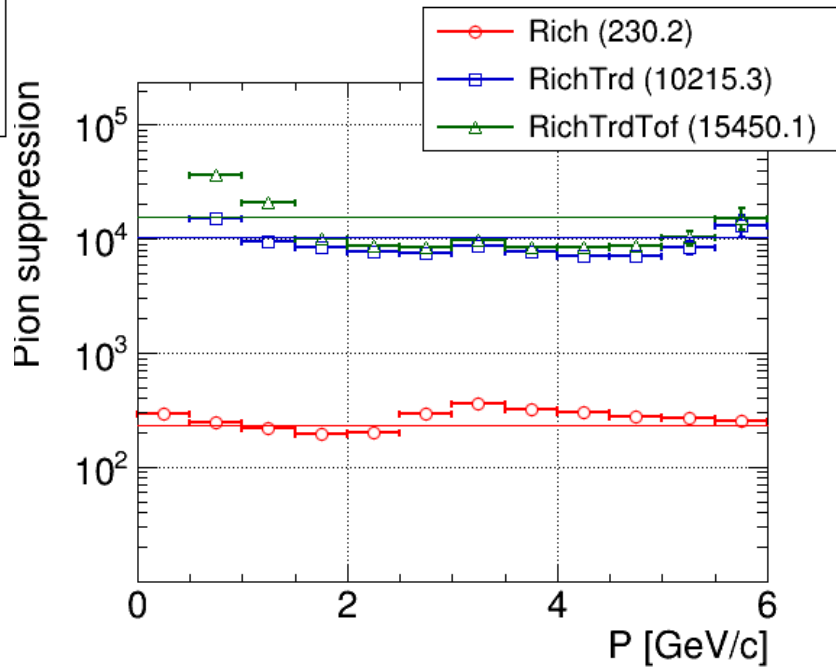
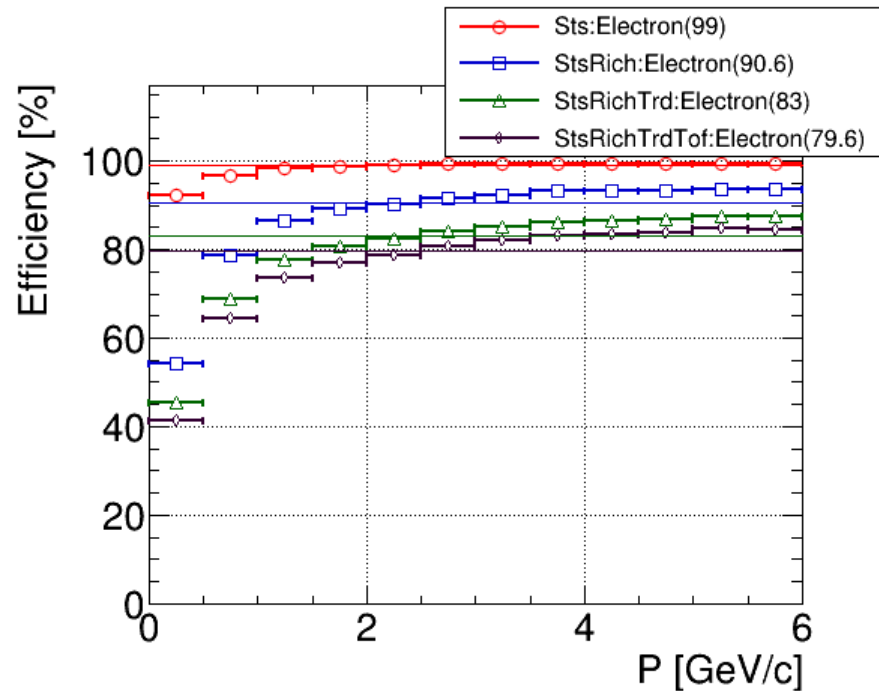
- Many  $\pi^0$  are created, decaying into  $2\gamma$  or  $\gamma e^+e^-$
- A lot of material is deposited before the RICH  
→ enhancement of  $\gamma$  conversion and secondary electrons
- Secondaries are seen in RICH and TRD and can easily be matched to tracks of charged pions
- Suppression of background is difficult → good tracking is essential for background suppression

# Track Selection for Di-Electron Analysis at CBM



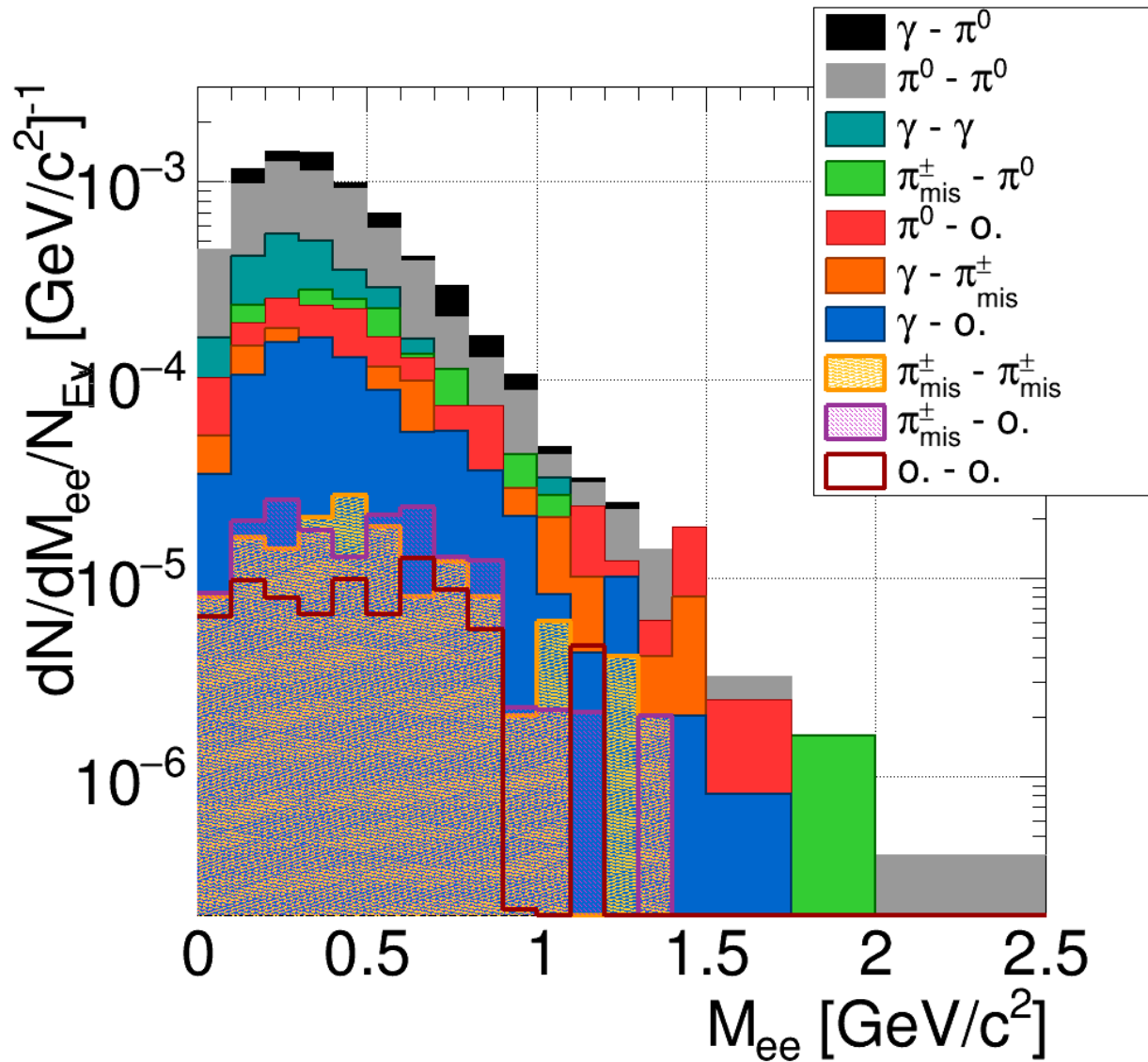
Sequence of Analysis cuts used for Di-Electron Analysis.

# Performance



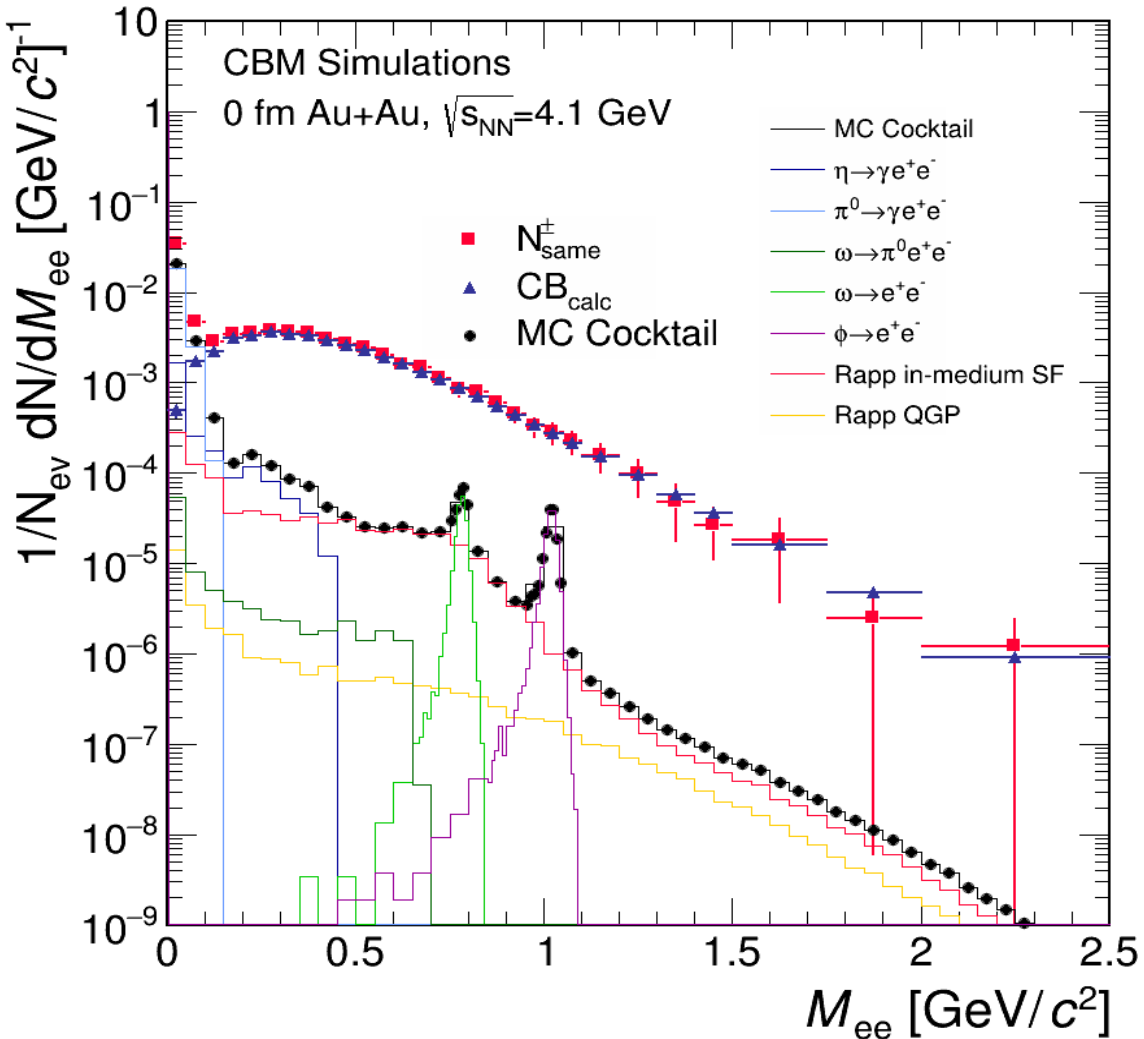
- Efficiency for electrons (in geometrical acceptance) to be reconstructed in all detectors  $\varepsilon \approx 80\%$
- Pion suppression  $\approx 15000$   $\left( s_{\pi} = \frac{\text{\#reconstructed pions}}{\text{\# rec. pions that passed EI-ID step}} \right)$
- Signal-to-Background ratio S/BG  $\approx 1/100$

# Current Status of Di-Electron Analysis



- Contributions to the background are dominated by physical background, i.e. electrons from  $\gamma$  conversion and  $\pi^0$  decay
- Also misidentified pions form a large part of the background

# Current Status of Di-Electron Analysis



- Ratio  $S/BG \approx 1/100$   $\rightarrow$  not possible to extract signal by means of e.g. see any peaks in  $N_{\text{same}}^{\pm}$  ( $= B_{\text{MC}} + \text{MC Cocktail}$ ) spectrum.
- Estimate background with mathematical expression ( $CB_{\text{calc}}$ , calculated combinatorial background) and subtract it from total  $e^+e^-$  spectra.

$$CB_{\text{calc}} = 2 k \sqrt{B^{++} B^{--}}, \quad B^{++} = e^+ e^+ \text{ yields from same events}$$

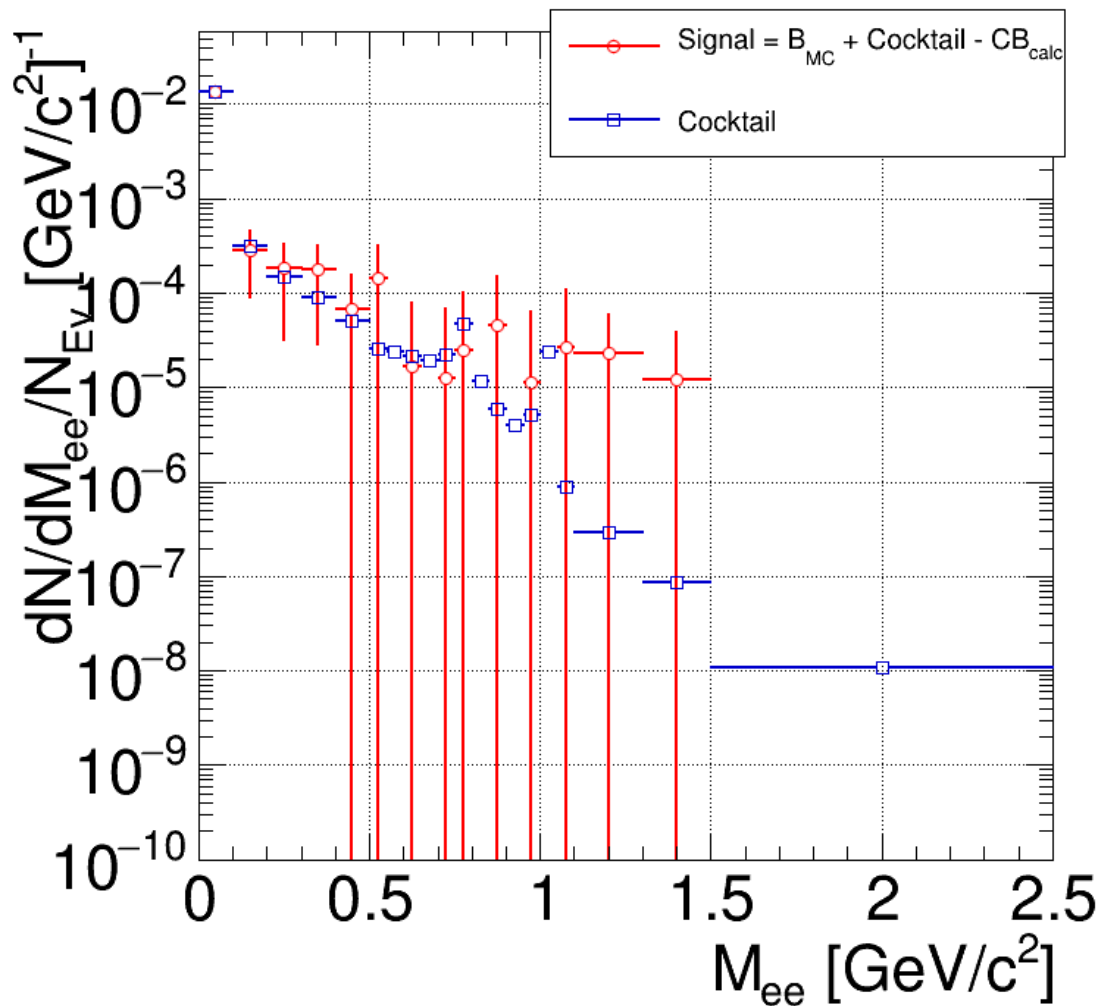
$$k = \frac{b^{\pm}}{2 \sqrt{b^{++} b^{--}}}, \quad b^{++} = e^+ e^+ \text{ yields from mixed events}$$

- Problem in our simulations:
  - Two large numbers are subtracted to get a small number as result
  - not sufficient statistics ( $5 \times 10^6$  events)

$\rightarrow$  large fluctuations in calculated signal



# Current Status of Di-Electron Analysis



➔ Large fluctuations in calculated signal

▪ Result does not reflect the true signal



▪ Idea: Enhance statistics by implementing Fast Simulation techniques (Random Events) to enable large statistics for constructing a background with small fluctuations

# Implementation of a Fast Simulation (Random Event) Procedure

[Andreas Salzburger: *Fast Simulation in ATLAS*; talk; 2013]

- Fast Simulations are based generally on approximations of geometry / models and parametrisations of outputs.
- Here: use output of „Slow Simulations“ as basis to create large numbers of randomly generated events (via using `GetRandom()`), separately for each particle or charge
- Which parameters are needed to construct the background?

$$M_{ee} = 2 \sqrt{P_+ \cdot P_-} \cdot \sin\left(\frac{\vartheta}{2}\right)$$

→ Hence, only two parameters are needed:

- **Multiplicity**: Occurrence of a particle per event after electron-identification
- **3D Momentum** distribution of that particle

How to speed up simulation (1)



approximate geometry



optimise transport and navigation

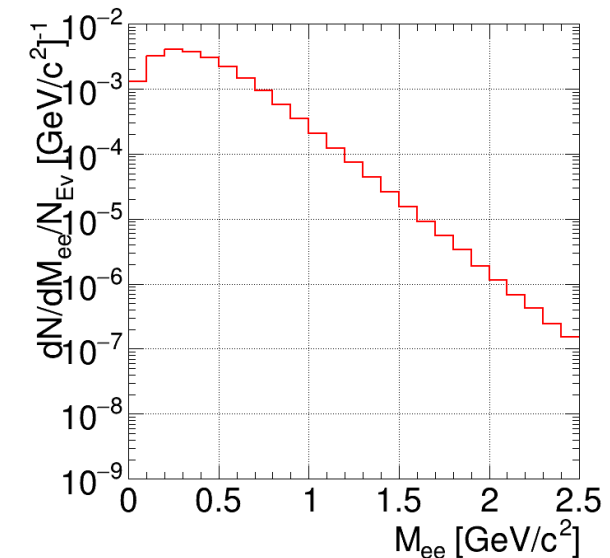
$\pi \approx 3$

approximate models

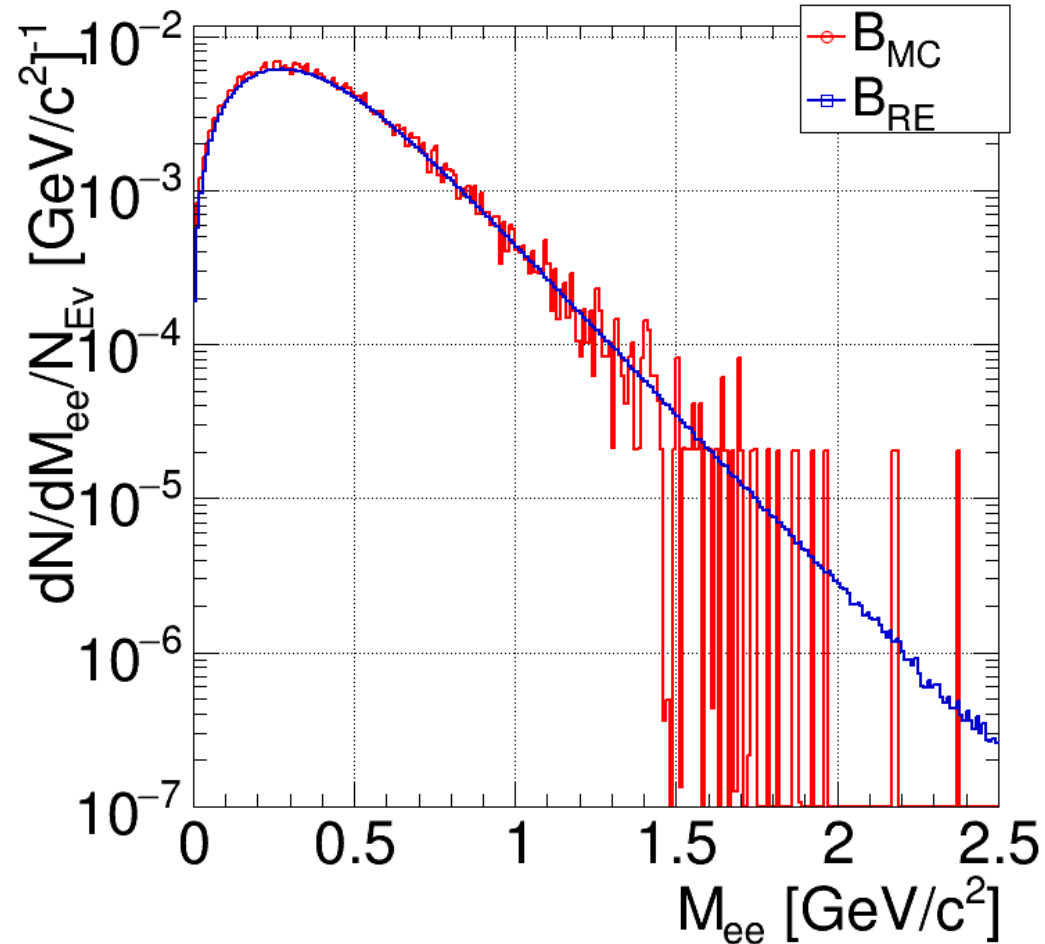


parameterisations

## Background

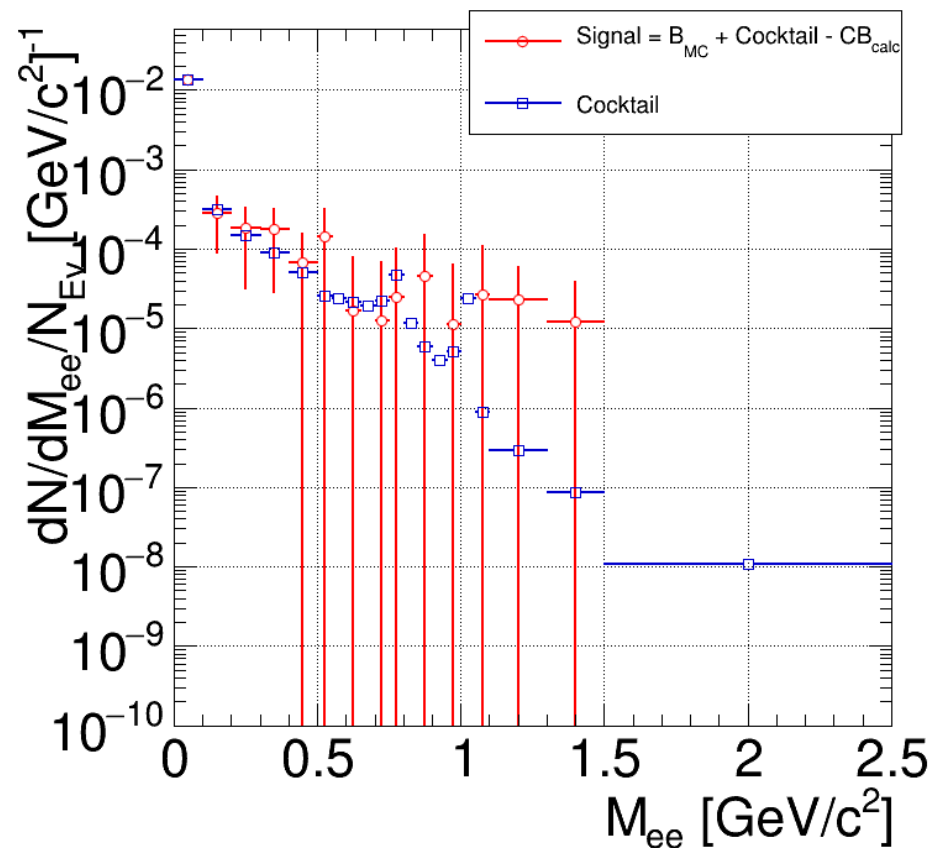
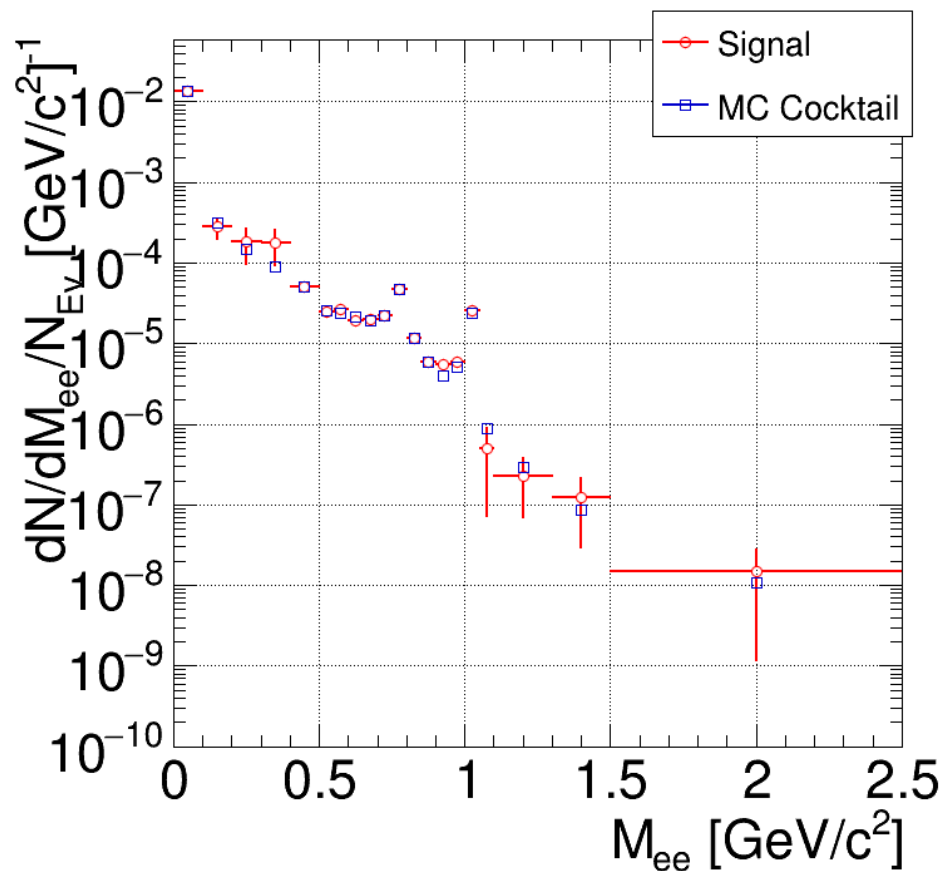


# Implementation of a Fast Simulation (Random Event) Procedure



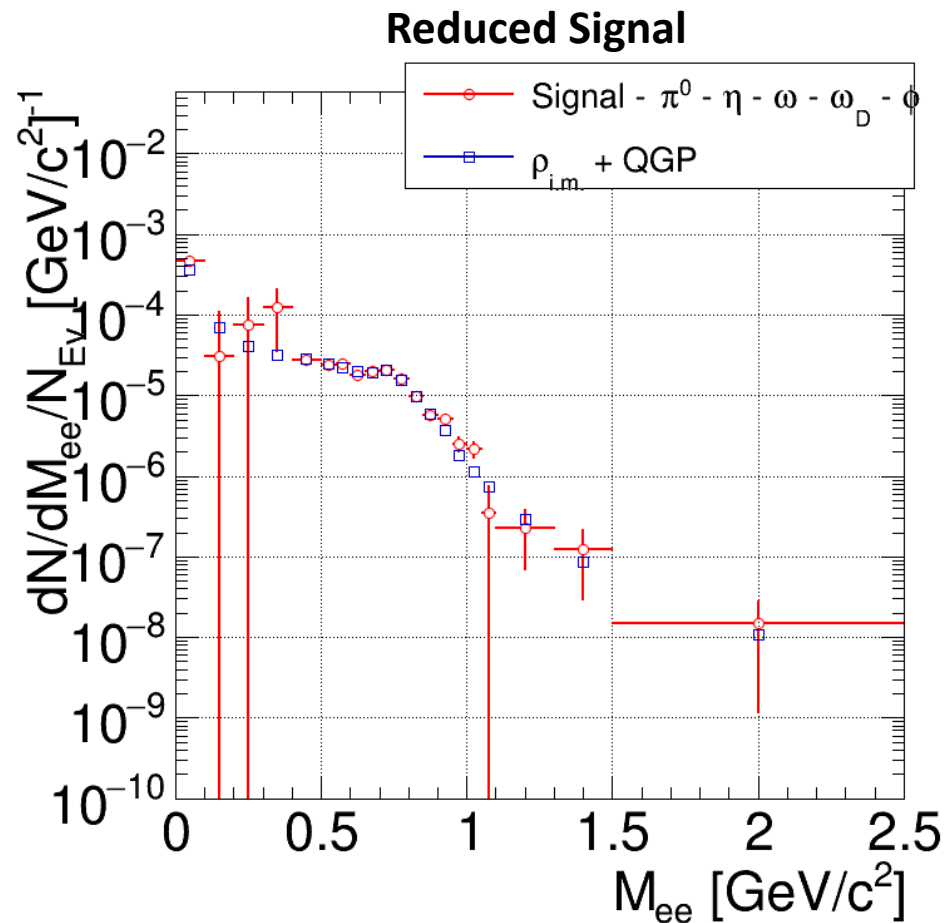
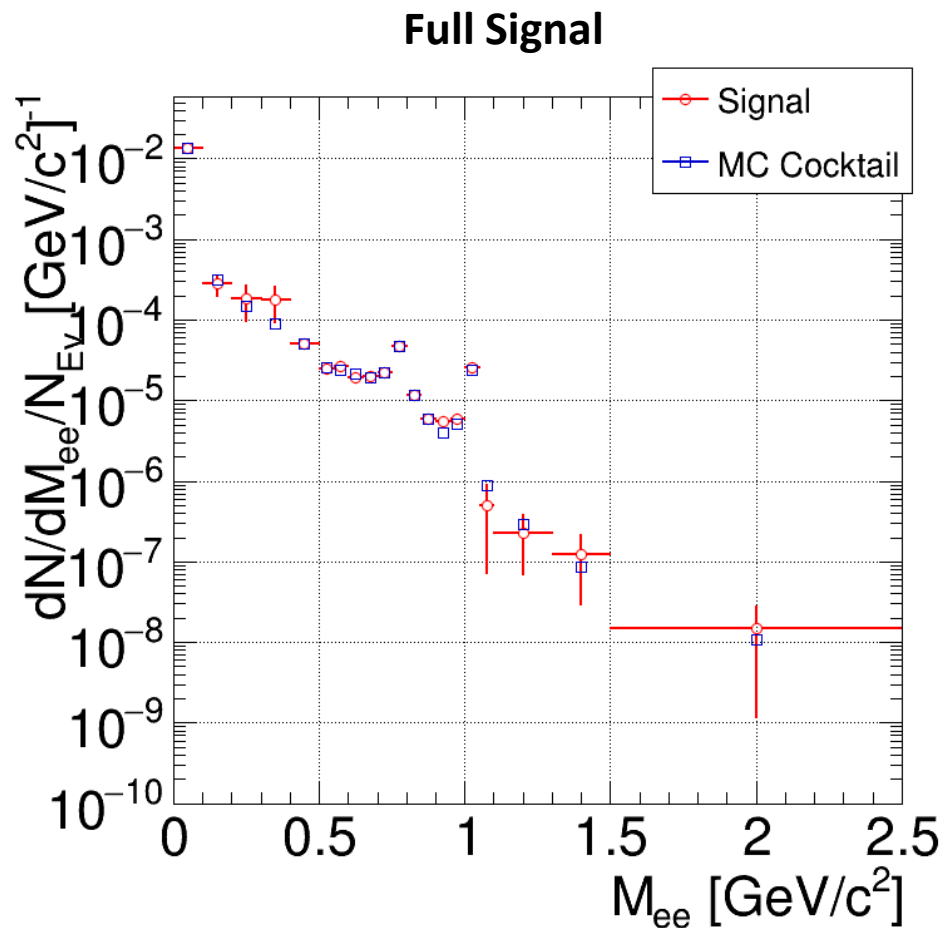
**Conventional Background  $B_{MC}$  with a statistics of  $5 \times 10^6$  compared to the background obtained by Random Event Techniques ( $B_{RE}$ ) with a statistics of  $20 \times 10^9$  events.**

# Result



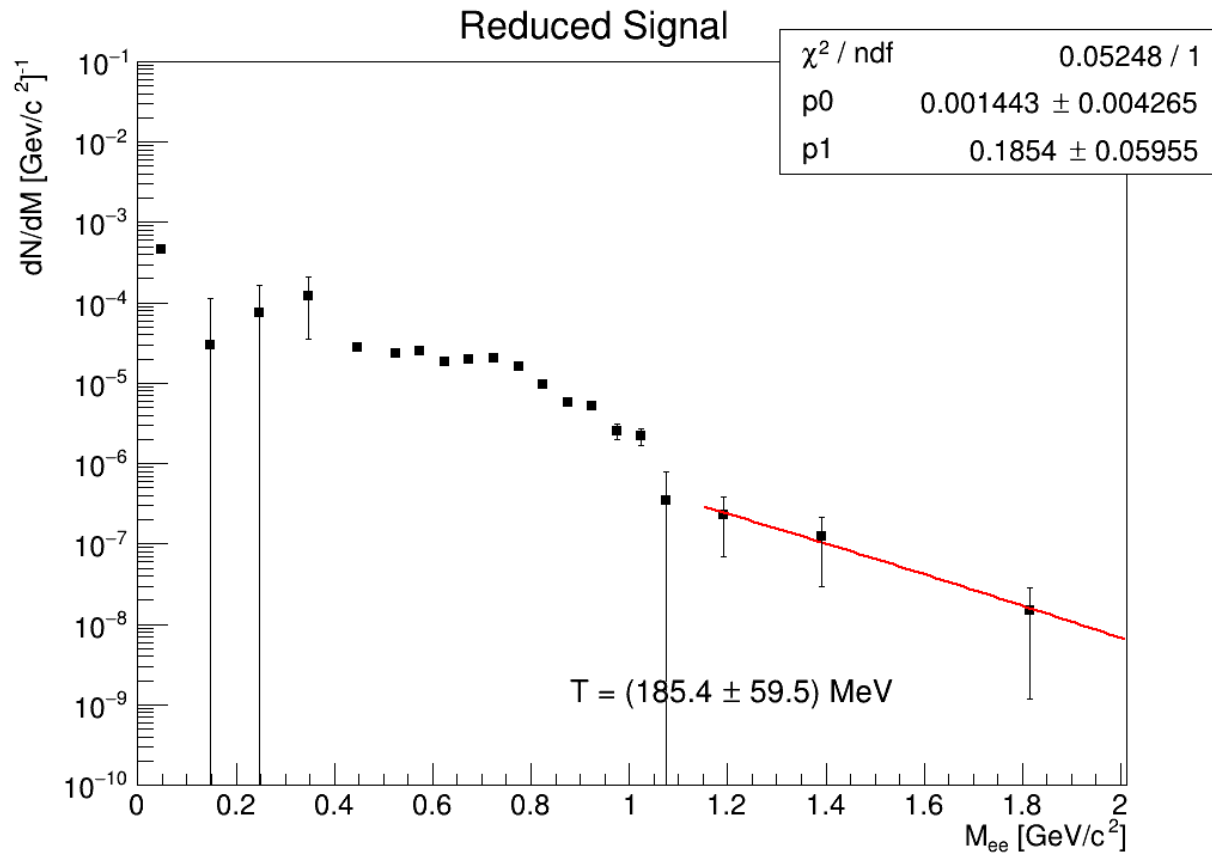
Signal (red), calculated by subtracting the Calculated Combinatorial Background ( $CB_{calc}$ ) from the  $e+e-$  yield, obtained by Random Event techniques (left) and conventional methods (right), in comparison to the MC cocktail (blue).

# Reduced Signal



Right: „Reduced“ signal: Obtained signal minus electrons from known sources ( $\pi^0$ ,  $\eta_D$ ,  $\omega$ ,  $\omega_D$ ,  $\phi$ ; red). Remain should only electrons from in-medium rho ( $\rho_{i.m.}$ ) and QGP. In blue: MC input  $\rho_{i.m.} + \text{QGP}$ .  
From comparison with NN references at masses below 1 GeV/c<sup>2</sup> the excess yield can be determined.

# Temperature of the Medium



Reduced Signal with temperature fit.

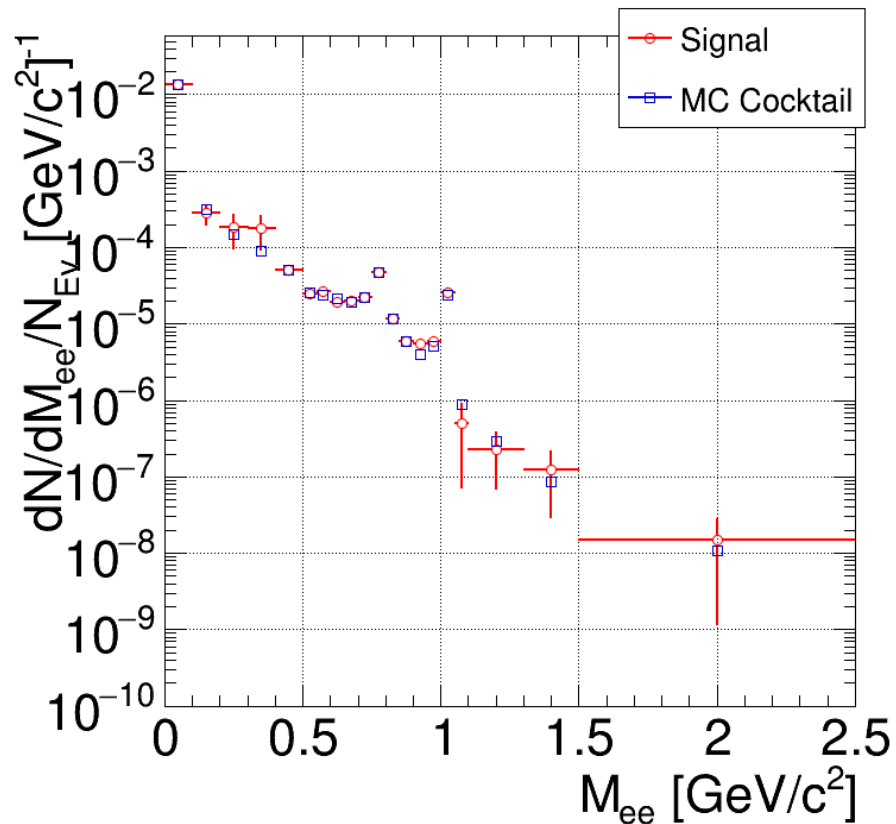
if  $M \gg T$ :

$$\frac{dN}{dM} \propto (MT)^{3/2} \exp(-M/T)$$

- Acceptance and efficiency corrections are not applied yet in these results (bias  $\approx 8 \text{ MeV}$ ).
- Location of data points is corrected due to asymmetric bin population to get true fit results <sup>1)</sup>

<sup>1)</sup> G.D. Lafferty, T.R. Wyatt: "Where to stick your data points: The treatment of measurements within wide bins". *Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment*, Volume 355, Issues 2–3, 1995, Pages 541-547, ISSN 0168-9002, [https://doi.org/10.1016/0168-9002\(94\)01112-5](https://doi.org/10.1016/0168-9002(94)01112-5).

# Statistical Errors



Calculated signal with statistical error bars. In the IMR, the size of the error is about the size of the signal itself.

- Statistical errors calculated for quick energy scan at first year of CBM running (4-5 days beam each for 5-6 energies with moderate rate)
- In last bin (1.5-2.5 GeV/c<sup>2</sup>):

$$\frac{S}{N} \approx \frac{1}{300}$$

$$N \approx 60,000^{1)} \rightarrow \Delta N = \sqrt{N} = 245$$

$$S = N - \text{CB}_{calc} \rightarrow \Delta S \approx \Delta N^{2)} = 245 \approx S = 200$$

- Ratio S/BG will be improved: e.g. MVD not included here yet (reduce contributions of  $\gamma$  and  $\pi^0$ ); better rejecting of pions and protons; etc.

<sup>1)</sup> for full statistics of  $20 \times 10^9$  events

<sup>2)</sup>  $\Delta \text{CB}_{calc} \ll \Delta S$  because of any wanted mixing depth

# Summary and Outlook

- Feasibility for Di-Electron measurement is shown
- Fast Simulation procedures were developed to enable realistic studies
- Suppression of background is difficult; improvements are ongoing and we are on well that way
- First year planned for quick energy scan; Thorough measurements for each energy will follow

*Thank you for  
your attention!*

Thanks to:

Claudia Höhne, Jan-Hendrik Otto, Marten Becker